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Attorney Docket No. 2-1226-065  
PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Robert W. Allington

Ser. No. 10/801,409

Filed: March 16, 2004

GAU: 1723

For: IMPROVED METHOD AND APPARATUS  
TO ENHANCE THE SIGNAL TO NOISE  
RATIO IN CHROMATOGRAPHYSUPPLEMENTAL LIST OF MATERIAL  
INFORMATION TRANSMITTALCommissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Applicant herein respectfully submits the enclosed supplemental prior art. This prior art is from a Partial European Search Report for the corresponding European patent application. A copy of the Search Report is also enclosed, and a copy of the cited references.

Respectfully submitted,

Robert W. ALLINGTON

By:

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Fax: 515-288-4860I, \_\_\_\_\_, do hereby certify that the foregoing is a true and correct copy of the original as submitted to the United States Patent and Trademark Office, on August 25, 2004.

Form PTO-1449  
(REV. 7-80) U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. (ORNEY) NO. 2-1226-065

SERIAL NO. 10/801,409

LIST OF MATERIAL INFORMATION CITED  
BY APPLICANT

APPLICANT

Robert W. Allington

FILING DATE

March 16, 2004

GROUP

## U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL | DOCUMENT NUMBER  | DATE       | NAME     | CLASS | SUB-<br>CLASS | FILING DATE<br>IF APPROPRIATE |
|---------------------|------------------|------------|----------|-------|---------------|-------------------------------|
| /D.C./              | AA 5 1 4 1 6 0 9 | 08-25-1992 | Sweedler |       |               |                               |
| /D.C./              | AB 5 5 9 1 6 4 4 | 01-07-1997 | Karmen   |       |               |                               |
|                     | AC               |            |          |       |               |                               |
|                     | AD               |            |          |       |               |                               |
|                     | AE               |            |          |       |               |                               |
|                     | AF               |            |          |       |               |                               |
|                     | AG               |            |          |       |               |                               |
|                     | AH               |            |          |       |               |                               |
|                     | AI               |            |          |       |               |                               |

## FOREIGN PATENT DOCUMENTS

|        | DOCUMENT NUMBER  | DATE       | COUNTRY | CLASS | SUB-<br>CLASS | TRANSLATION<br>YES NO |
|--------|------------------|------------|---------|-------|---------------|-----------------------|
| /D.C./ | AL 9 9 1 7 1 0 4 | 04-08-1999 | WIPO    |       |               | XX                    |
| /D.C./ | AM 3 0 1 0 5 2 4 | 02-06-2003 | WIPO    |       |               | XX                    |

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

|    |  |
|----|--|
| AR |  |
| AS |  |
| AT |  |

EXAMINER /David Chong/

DATE CONSIDERED

01/18/2008

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.